## Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
09/912,721	CHEN ET AL.
Examiner	Art Unit

JOHN J. LEE

2618

SEARCHED					
Class	Subclass	Date	Examiner		
455	560,445 453,434 561,424 514,507	6/11/2008	J.L		
455	510,515	6/11/2008	J.L		
455	450,452.1	6/11/2008	J.L		
370	335,336	6/11/2008	J.L		

Class	Subclass	Date	Examine

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
•	DATE	EXMR	
EAST	6/11/2008	J.L	